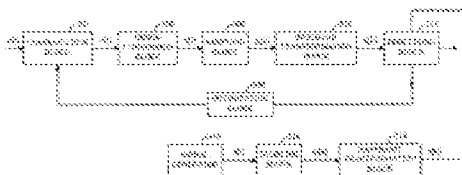


**METHOD AND APPARATUS FOR WAVEFORM QUALITY MEASUREMENT****Publication number:** EP1342335**Publication date:** 2003-09-10**Inventor:** MONTOJO JUAN (US); SINDHUSHAYANA  
NAGABHUSHANA (US); BLACK PETER (US)**Applicant:** QUALCOMM INC (US)**Classification:****- International:** **H04B1/707; H04B1/00; H04B17/00; H04B1/707;**  
**H04B1/00; H04B17/00; (IPC1-7): H04L1/24****- European:** H04B17/00B1**Application number:** EP20010990097 20011213**Priority number(s):** WO2001US47758 20011213; US20000738586  
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Abstract not available for EP1342335

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A method and an apparatus for waveform quality measurement are disclosed. An actual signal, representing a waveform channelized both in time and in code is generated by, e.g., an exemplary HDR communication system. Test equipment generates an ideal waveform corresponding to the actual waveform. The test equipment then generates an estimate of offsets between parameters of the actual waveform and the ideal waveform, and the offsets are used to compensate the actual waveform. The test equipment then evaluates various waveform quality measurements utilizing the compensated actual waveform quality measurements as well as conceptual and practical examples of processing of the actual waveform and the corresponding ideal waveform by the test equipment are disclosed. The disclosed method and apparatus may be extended to any waveform channelized both in time and in code regardless of the equipment that generated the waveform.

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